

Search Notes

Application/Control No.

10/774,039

Examiner

Le Nguyen

Applicant(s)/Patent under
Reexamination

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Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
715	734	9/17/2007	LVN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/734		9/17/2007	LVN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
confirmed allowance w/Ba Huynh	9/14/2007	LVN
IEEE Xplore; ACM Digital Library	9/14/2007	LVN
EPO, JPO	9/17/2007	LVN
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